Search Notes



Application/Control No.

Applicant(s)/Patent Under Reexamination

10824980

DEWDNEY ET AL.

Examiner

Jaisle, Cecilia M

Art Unit

1624

Notes	Date	Examiner	
Searched in STN by STIC	07-19-06	Cecilia Jaisle	
Inventoir names searched in PALM	8-28-06	Cecilia Jaisle	
U.S. Patent and Trademark Office		Part of Paper No.:	

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